

Press Release

Date: February 2011
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Measure Flatnesses, Parallelisms and Step Heights Reliably in Quality Control

Engine manufacturers are under pressure to reduce emissions and improve reliability whilst retaining high fuel efficiency. This requires fine manufacturing tolerances that must be checked during production with high repeatability and rapidly in order to keep up with cycle times. Flatness and parallelism measurements facilitate the three-dimensional characterization of these surfaces. Tactile measurement methods used until now frequently require too much time. This is why, according to Dr. Wilfried Bauer at Polytec GmbH, optical metrology is gaining ever greater importance in this area: with the aid of white light interferometry, relatively large surfaces can be characterized with small measurement uncertainties. Using this method, the 3D profile of a workpiece can be determined within a few seconds. Polytec has developed tailor-made solutions with its TMS TopMap white light interferometers: step heights, parallelisms or flatnesses of even relatively deep-lying surfaces can be determined rapidly, simply and at reasonable cost. At the same time, a measurement station can also be supplied close to the production line even integrated into the line. "The early detection of faults or trends during the production process helps customers save costs and increase product quality", said Sales Engineer Tobias Wiesendanger from Polytec. According to Tobias, reasons for the success of the TMS TopMap series include easy operation and ability to be integrated into the line.

More information: www.topmap.info

Publication free of charge

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